

Notice of References Cited	Application/Control No. 10/801,723	Applicant(s)/Patent Under Reexamination YAMANAKA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,403,280	06-2002	Yamahara et al.	430/270.1
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	E	US-6,548,221	04-2003	Uetani et al.	430/270.1
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	H	US-6,146,806	11-2000	Maeda et al.	430/170
	I	US-6,777,511	08-2004	Ochiai et al.	526/173
	J	US-6,849,381	02-2005	Barclay et al.	430/270.1
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	O	EP 1143299 A1	10-2001	European Patent	UETANI et al.	G03F 07/039
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